

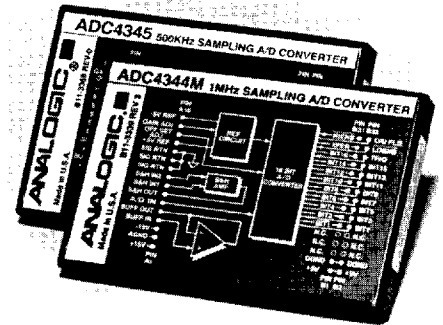
Very High Speed 16-Bit, 1 MHz and 500 kHz Sampling A/D Converters

Description

The ADC4344 and ADC4345 are complete 16-bit, 1 MHz and 500 kHz A/D converter subsystems with a built-in sample-and-hold amplifier in a space-saving 2.5" x 3.5" x 0.44" package. They offer pin-programmable input voltage ranges of $\pm 2.5V$, $\pm 5V$ and 0 to $+10V$. They are designed for use in applications requiring high speed and high resolution front ends such as ATE, digital oscilloscopes, medical imaging, radar, sonar, and analytical instrumentation. The ADC4344 is capable of digitizing a 500 kHz signal at a 1 MHz sampling rate with a guarantee of no missing codes from $0^{\circ}C$ to $+60^{\circ}C$. Equally impressive in frequency domain applications, the ADC4345 features 95 dB signal-to-noise ratio with input signals from DC to 100 kHz.

The ADC4344 and ADC4345 utilize the latest surface-mount technologies to produce a cost effective, high performance part in a 2.5" x 3.5" fully shielded package. They are designed around a two-pass, sub-ranging architecture that integrates a low distortion sample-and-hold amplifier, precision voltage reference, ultra-stable 16-bit linear reference D/A converter, all necessary timing circuitry and tri-state CMOS/TTL compatible output lines for ease of system integration. The converters also offer an optional high-speed, low-noise input buffer for applications requiring high input impedance.

Superior performance and ease-of-use of these converters make an ideal solution for those applications requiring a sample-and-hold amplifier directly at the input to the A/D converter. Having the S/H amplifier integrated with the A/D converter benefits the system designer in two ways. First, the S/H is designed specifically to complement the performance of the A/D converter; for example, the acquisition time, hold mode settling, and droop rate are optimized for the A/D converter, resulting in exceptional overall performance. Second, the designer achieves true 16-bit performance, avoiding degradation due to ground loops, signal coupling, jitter, and digital noise introduced when separate S/H and A/D converters are interconnected. Furthermore, the accuracy, speed, and quality of the ADC4344 and ADC4345 are fully ensured by thorough, computer controlled factory tests of each unit.



Features

- ▢ Built-in S/H Amplifier
- ▢ Unique 2-Pass Sub-Ranging Architecture
- ▢ 16-Bit Resolution
- ▢ 1 MHz and 500 kHz Conversion Rate
- ▢ 0.003% Maximum Integral Nonlinearity
- ▢ No Missing Codes
- ▢ Peak Distortion: -99 dB (100 kHz Input)
- ▢ Signal to Noise Ratio: 100 kHz Input 92 dB, ADC4344; 95 dB, ADC4345
- ▢ Total Harmonic Distortion: -93 dB (100 kHz Input)
- ▢ TTL/CMOS Compatibility
- ▢ Low Noise
- ▢ Compact Size: 2.5" x 3.5" x 0.44"
- ▢ Electromagnetic/Electrostatic Shielding

Applications

- ▢ Digital Signal Processing
- ▢ Sampling Oscilloscopes
- ▢ Automatic Test Equipment
- ▢ High-Resolution Imaging
- ▢ Analytical Instrumentation
- ▢ Medical Instrumentation
- ▢ CCD Detectors
- ▢ IR Imaging
- ▢ Sonar
- ▢ Radar

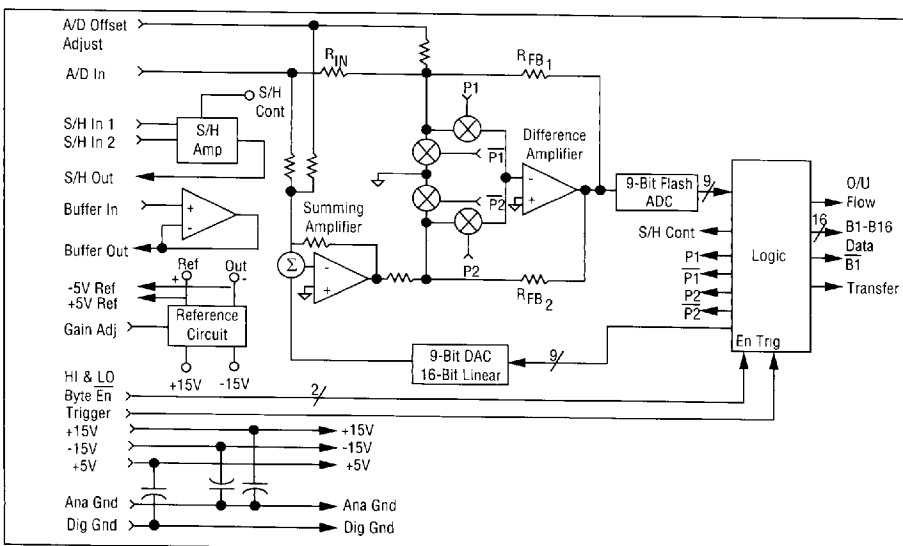


Figure 1. Functional Block Diagram.

ANALOGIC

The World Resource
for Precision Signal Technology

0816970 0003153 184

ADC4344/ADC4345

Specifications ⁽¹⁾

ANALOG INPUT

Input Voltage Range

Bipolar

±2.5V, ±5V

Unipolar

0 to +10V

Max. Input Without Damage

±15.5V Typ.

S/H Direct Input Resistance

2.5 kΩ Typ.

Ext. Offset and Gain Adj. Sensitivity

2 mV/V

INPUT BUFFER ²

Input Bias Current

10 nA Max.

Input Resistance

100 MΩ Typ.

Input Capacitance

10 pF Typ.

F.S. Settling Time

800 ns Typ. to 0.0015%

DIGITAL INPUTS

Compatibility

TTL, HCT, and ACT

Logic "0"

+0.8V Max.

Logic "1"

+2.0V Min.

Trigger

Positive Edge Triggered

Loading

1 TTL Load Min.

Pulse Width

100 ns Min.

High Byte Enable

Active Low, B1-B8, B1

Low Byte Enable

Active Low, B9-B16

INTERNAL REFERENCE

Voltage

±5V, ±0.1% Max.

Stability

10 ppm/°C Max.

Available Current ³

0.5 mA Max.

DIGITAL OUTPUTS

Fan-Out

1 TTL Load

Logic "0"

+0.4V Max.

Logic "1"

+2.4V Min.

Output Coding

Binary, Offset Binary, 2's Comp.

Transfer Pulse

Data valid on positive edge

Over/Under Flow

Valid = logic "0" (occurs only when ±FS have been exceeded)

DYNAMIC CHARACTERISTICS ⁴

Maximum Throughput Rate

500 kHz Min. (ADC4345)

1.0 MHz Min. ((ADC4344)

A/D Conversion Time

1.2 μs Typ. (ADC4345)

620 ns Typ. (ADC4344)

S/H Acquisition Time

800 ns Typ. (ADC4345)

380 ns Typ. (ADC4344)

S/H Aperture Delay

15 ns Max.

S/H Aperture Jitter

10 ps rms Max.

S/H Feedthrough ⁵

−90 dB Max.; −96 dB Typ.

Full Power Bandwidth

1.5 MHz Min. (ADC4345)

3.0 MHz Min. (ADC4344)

Small Signal Bandwidth

2.8 MHz Typ. (ADC4345)

4.0 MHz Typ. (ADC4344)

Slew Rate

50V/μs Typ. (ADC4345)

100V/μs Typ. (ADC4344)

Signal to Noise Ratio ⁶

100 kHz input @ 0 dB

92 dB Min., 95 dB Typ. (ADC4345)

89 dB Min., 92 dB Typ. (ADC4344)

540 kHz input @ −10 dB (ADC4344)

79 dB Min., 82 dB Typ.

Peak Distortion ⁶

100 kHz input @ 0 dB

−92 dB Max., −99 dB Typ.

@ −20 dB

−92 dB Typ.

540 kHz input @ −10 dB (ADC4344)

84 dB Min., 91 dB Typ.

Total Harmonic Distortion ⁶

20 kHz input @ 0 dB

−90 dB Max., −97 dB Typ.

@ −20 dB

−82 dB Typ.

100 kHz input @ 0 dB

−86 dB Max., −93 dB Typ. (ADC4345)

−86 dB Max., −97 dB Typ. (ADC4344)

@ −20 dB

−82 dB Typ.

540 kHz input @ −10 dB (ADC4344)

−79 dB Min., −86 dB Typ.

THD + Noise ⁷

20 kHz input @ 0 dB

89 dB Min., 92 dB Typ. (ADC4345)

87 dB Min., 90 dB Typ. (ADC4344)

@ −20 dB

75 dB Typ. (ADC4345)

72 dB Typ. (ADC4344)

100 kHz input @ 0 dB

86 dB Min., 91 dB Typ. (ADC4345)

84 dB Min., 89 dB Typ. (ADC4344)

@ −20 dB

75 dB Typ. (ADC4345)

72 dB Typ. (ADC4344)

540 kHz input @ −10 dB (ADC4344)

76 dB Min., 81 dB Typ.

Step Response ⁸

800 ns Max. to 1 LSB

TRANSFER CHARACTERISTICS

Resolution

16 bits

Quantization Error

±0.5 LSB Max.

Integral Nonlinearity

±0.003% FSR Max.

Differential Nonlinearity

±0.75 LSB Max.

Monotonicity

Guaranteed

No Missing Codes

Guaranteed 0°C to +60°C

Offset Error

±0.1% FSR Max. (Adj. to Zero)

Gain Error

±0.1% FSR Max. (Adj. to Zero)

Noise w/o Buffer ⁹

10V p-p FSR

50 μV rms Typ., 56 μV rms Max. (ADC4345)

70 μV rms Typ., 80 μV rms Max. (ADC4344)

5V p-p FSR

35 μV rms Typ., 40 μV rms Max. (ADC4345)

50 μV rms Typ., 55 μV rms Max. (ADC4344)

Noise including Buffer ⁹

10V p-p FSR

56 μV rms Typ., 70 μV rms Max. (ADC4345)

79 μV rms Typ., 100 μV rms Max. (ADC4344)

5V p-p FSR

42 μV rms Typ., 50 μV rms Max. (ADC4345)

60 μV rms Typ., 70 μV rms Max. (ADC4344)

STABILITY (0°C TO 60°C)

Differential Nonlinearity TC

±1 ppm/°C Max.

Offset TC

±10 ppm/°C Max., ±5 ppm/°C Typ.

Gain TC

±10 ppm/°C Max., ±5 ppm/°C Typ.

Warm-Up Time

5 Min. Max.

Supply Rejection per % change in any supply

Offset

±10 ppm/% Max., ±2 ppm/% Typ.

Gain

±10 ppm/% Max., ±2 ppm/% Typ.

POWER REQUIREMENTS

±15V Supplies

14.55V Min., 15.45V Max.

+5V Supplies

+4.75V Min., +5.25V Max.

+15V Current Drain

100 mA Typ.

−15V Current Drain

100 mA Typ.

+5V Current Drain

80 mA Typ.

Total Power Consumption

3.4W Typ.

ENVIRONMENTAL & MECHANICAL

Specified Temp. Range

0°C to 60°C

Storage Temp. Range

−25°C to 80°C

Relative Humidity

85%, non-condensing to 60°C

Dimensions

2.5" x 3.5" x 0.44"
(63.5 x 88.9 x 11.18 mm)

Shielding

Electromagnetic 6 sides

Electrostatic 6 sides

Case Potential

Ground

0816970 0003154 010

SPECIFICATIONS

Notes

1. All specifications guaranteed at 25°C unless otherwise noted and supplies at $\pm 15\text{V}$ and $\pm 5\text{V}$.
2. The input buffer need only be used when a high impedance input is required.
3. Reference Load to remain stable during conversion.
4. Dynamic characteristics on $\pm 5\text{V}$ input range and without input buffer unless otherwise noted.
5. Measured with a full scale step input with a $20\text{V}/\mu\text{s}$ rise time
6. See performance testing
7. THD + noise represents the ratio of the RMS value of the signal to the total RMS noise below the Nyquist plus the total harmonic distortion up to the 100th harmonic with an analysis bandwidth of DC to the Nyquist rate.
8. Step response represents the time required to achieve the specified accuracies after an input full scale step change.
9. Includes noise from S/H and A/D converter.

(Specifications subject to change without notice.)

Input Scaling

The ADC4344 and ADC4345 can be configured for three input voltage ranges: 0 to $+10\text{V}$, $\pm 2.5\text{V}$, and $\pm 5\text{V}$. The Analog input range should be scaled as close as possible to the maximum input to utilize the full dynamic range of the converter. Figure 2 describes the input connections.

PIN #	A8	A9
RANGE	S/H IN 1	S/H IN 2
0V to $+10\text{V}$	Input	-5V Ref
$\pm 5\text{V}$	Input	SIG RTN
$\pm 2.5\text{V}$	Input	Input

Figure 2. Input Scaling Connections.

Coding and Trim Procedure

Figure 4 shows the output coding and trim calibration voltages of the A/D converter. For two's complement operation, simply use the available B1 (MSB) instead of B1 (MSB). Refer to Figure 3 for use of external offset and gain trim potentiometers. Voltage DACs with a $\pm 10\text{V}$ output can be easily utilized when digital control is required. The input sensitivity of the external offset and gain control pins is 2 mV/V . If the external offset and gain adjust pins are not used, connect to pin A12.

To trim the offset of the AD converter, apply the offset voltage shown in Figure 4 for the appropriate voltage range. Adjust the offset trim potentiometer such that the 15 MSBs are "0" and the LSB alternates equally between "0" and "1" for the unipolar ranges or all 16 bits are in transition for the bipolar ranges.

To trim the gain of the ADC4345, apply the range (+FS) voltage shown in Figure 4 for the appropriate range. Adjust the gain trim potentiometer such that the 15 MSBs are "1" and the LSB alternates equally between "0" and "1".

To check the trim procedure, apply 1/2 full scale voltage for a unipolar range or $-$ full scale voltage for the bipolar ranges and check that the digital code is ± 1 LSB of the stated code.

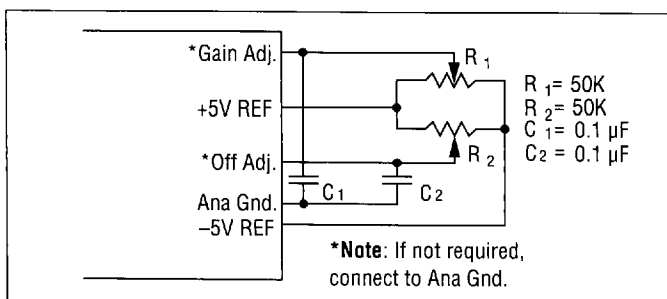


Figure 3. Offset and Gain Adjustment Circuit.

UNIPOLAR BINARY		0V TO $+10\text{V}$	
MSB	LSB		
+FS	1111111111111111*	=	$+9.99977\text{V}$
1/2 FS	1000000000000000	=	$+5.00000\text{V}$
Offset	0000000000000000*	=	$+0.00008\text{V}$
OFFSET BINARY		$\pm 2.5\text{V}$ input	$\pm 5\text{V}$ input
MSB	LSB		
+FS	1111111111111111*	=	$+2.49989\text{V}$
Offset	0000000000000000*	=	-0.00004V
+FS	1000000000000000*	=	-2.49996V
2'S COMPLEMENT		$\pm 2.5\text{V}$ input	$\pm 5\text{V}$ input
MSB	LSB		
+FS	0111111111111111*	=	$+2.49989\text{V}$
Offset	0000000000000000*	=	-0.00004V
$-FS$	1000000000000000*	=	-2.49996V

*denotes a 0/1 or 1/0 transition

Figure 4. Coding and Trim Calibration Table.

Layout Considerations

Because of the high resolution of the ADC4344/ADC4345 A/D converters, it is necessary to pay careful attention to the printed-circuit layout for the device. It is, for example, important to return analog and digital grounds separately to their respective power supplies. Digital grounds are often noisy or "glitchy", and these glitches can have adverse effects on the performance of the ADC4345 if they are introduced to the analog portions of the A/D converter's circuitry. At 16-bit resolution, the size of the voltage step between one code transition and the succeeding one for a 5V full scale range is only $76\text{ }\mu\text{V}$. It is evident that any noise in the analog ground return can result in erroneous or missing codes. It is important in the design of the PC board to configure a low-impedance ground-plane return on the printed-circuit board. It is only at this point, where the analog and digital power returns should be made common.

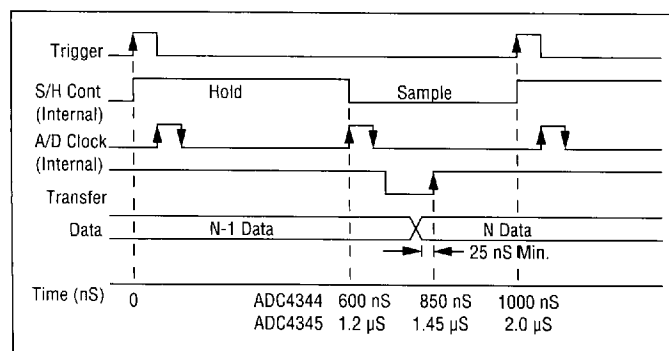


Figure 5. Timing Diagram.

The ADC4344 and ADC4345 are 16-bit sampling A/D converters with a throughput rate of up to 1 MHz. These converters are available in two externally configured full scale ranges of 5V p-p and 10V p-p. Both options are externally or user programmable for bipolar and unipolar inputs of $\pm 2.5V$, $\pm 5V$ and 0 to +10V. Two's complement format can be obtained by utilizing $\overline{B1}$ instead of B1.

To understand the operating principles of the A/D converter, refer to the timing diagram of Figure 5 and the simplified block diagram of Figure 6. The simplified block diagram illustrates the two successive passes in the sub-ranging scheme of the AD converter.

The A/D converter section of the converters is factory trimmed and optimized to operate with a 10V p-p input voltage range. Scaling resistors at the S/H inputs configure the three input ranges and provide a S/H output voltage to the A/D converter of 10V p-p.

The first pass starts with a low-to-high transition of the trigger pulse. This signal places the S/H into the Hold mode and starts the timing logic. At this time, the internal logic locks out any additional triggers that may inadvertently occur and corrupt the conversion process until the routine is complete. The path of the 10V p-p input signal during the first pass is through a 5:1 attenuator circuit to the 9-bit ADC with an input range of 2V p-p. At 50 ns, the ADC converts the signal and the 9 bits are latched both into the logic as the MSBs and into the 16-bit accurate DAC for the second pass.

The second pass subtracts the 9-bit, 16-bit accurate DAC output and the S/H output with the result equal to the 9-bit quantization error of the DAC, or 19.5 mV p-p. This "error" voltage is then amplified by a gain of 25.6 and is now

0.5V p-p or 1/4 of the full scale range of the ADC allowing a 2-bit overlap safety margin. At approximately 1.2 μs , the DAC and the "error" amplifier have had sufficient time to settle to 16-bit accuracy and the amplified "error" voltage is then digitized by the ADC with the 9-bit second pass result latched into the logic. At this time the S/H returns to the sample mode to begin acquiring the next sample.

The 1/4 full scale range in the second pass produces a 2-bit overlap of the two passes. This is a scheme used in the A/D converter to provide an output word that is accurate and linear to 16 bits. This method corrects for any gain and linearity errors in the amplifying circuitry, as well as the 9-bit flash A/D converter. Without the use of this overlapping correction scheme, it would be necessary that all the components in the A/D converter be accurate to the 16-bit level. While such a design might be possible to realize on a laboratory benchtop, it would be clearly impractical to achieve on a production basis. The key to the conversion technique used in the A/D converter is the 16-bit accurate and 16-bit-linear D/A converter which serves as the reference element for the conversion's second pass. The use of proprietary sub-ranging architecture in the A/D converter results in a sampling A/D converter that offers unprecedented speed and transfer characteristics at the 16-bit level.

The ADC4345 has a 3-state output structure. Users can enable the eight MSBs and B1 with $\overline{HIBYTEN}$ and the eight LSBs with $\overline{LOBYTEN}$ (Both are active low). This feature makes it possible to transfer data from the A/D converter to an 8-bit microprocessor bus. However, to prevent the coupling of high frequency noise from the microprocessor bus into the A/D converter, the output data must be buffered (see Figure 11).

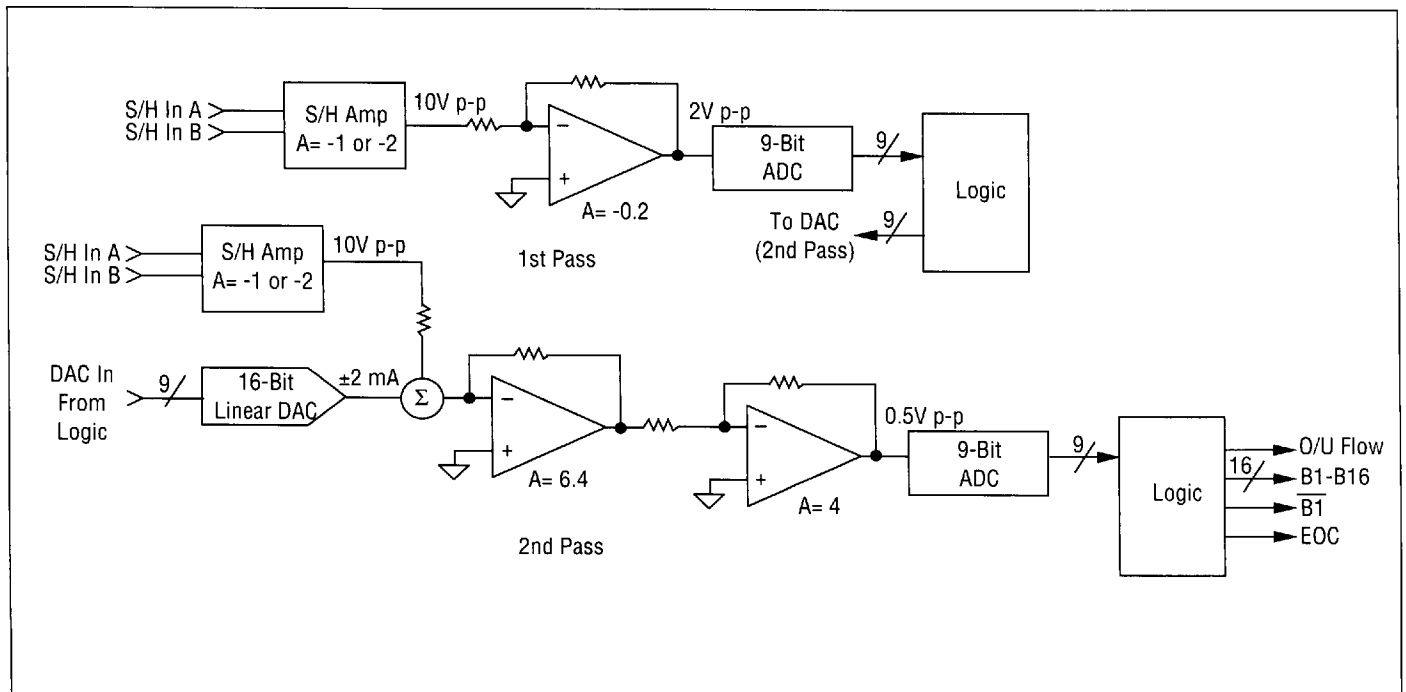


Figure 6. Operating Principle of the ADC4344 and ADC4345.

In order to guarantee that all ADC4344 and ADC4345s shipped meet or exceed published specifications, Analogic takes great efforts in performing a multitude of tests on each module prior to shipment. Such results are then sent to the customer in conjunction with each A/D converter as a testimony of the performance results.

Amplitude Domain Testing

The Amplitude Domain Testing is performed by means of proprietary Automatic Test Equipment inclusive of a 22-bit digital-to-analog converter, whose reference is traceable to the National Institute of Standards Technology. A block diagram is outlined in Figure 7. By means of this test equipment, Analogic can test such parameters as integral linearity, differential linearity, A/D converter noise, maximum positive and negative errors, conversion time, gain error, offset error, power supply current, power supply rejection. A typical "Amplitude Domain" data sheet is shown in Figure 9. For further information on the definitions of such specifications, please refer to the "Analogic Data Conversion Systems Digest".

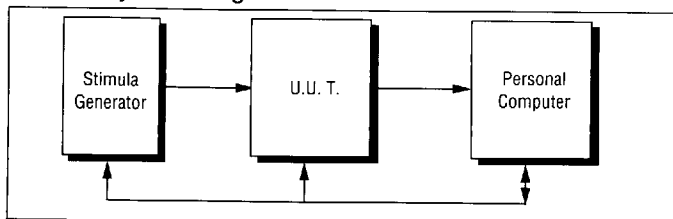


Figure 7. "Amplitude Domain" Test System.

Frequency Domain Testing

This test is performed to simulate real time applications where a constantly varying input signal is applied to the A/D converter. A block diagram of the Analogic "Frequency Domain" test system is shown in Figure 8. As a result, a data sheet, such as the one reproduced in Figure 10, is delivered to the customer with each A/D converter.

The data sheet is divided into two sections including the nature of the input data, the type of FFT performed and the results of the FFT test. This data can possibly be misleading if not thoroughly understood. For example, in an audio application, one of the most important parameters is the absence of aliased harmonic distortion. While harmonic distortion directly related to the fundamental does not produce audible discomfort, aliased harmonics can be very bothersome. Such characterization is not often provided or is calculated as part of the total harmonic distortion, thus, misleading the end user. Analogic definitions are summarized as follows:

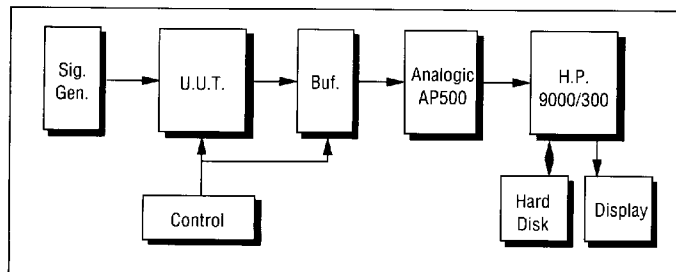


Figure 8. "Frequency Domain" Test System.

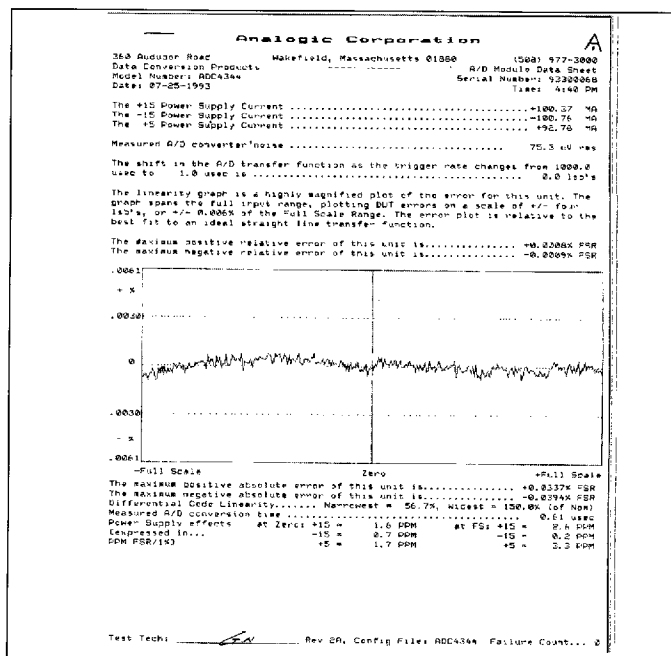


Figure 9. "Amplitude Domain" Data Sheet.

Peak Distortion: Ratio, expressed in dB, between the RMS value of the highest spurious spectral component below the Nyquist rate and the RMS value of the input signal.

$$\text{Peak Distortion} = 20 \log \frac{\text{RMS value of max. spurious component}}{\text{RMS value of input signal}}$$

Signal to Noise Ratio: Ratio, expressed in dB, between the RMS value of the signal and the total RMS noise below the Nyquist rate. Note that all frequency bins that are correlated with the test frequency are removed and replaced with an average of the remaining bins.

Total Harmonic Distortion: Ratio, expressed in dB, between the RMS sum of all harmonics up to the 100th harmonic and the RMS value of the signal.

Direct Harmonic Distortion: Ratio, expressed in dB, between the RMS sum of all the components below the Nyquist rate that are harmonically related to the signal and the RMS value of the signal.

Reflected Harmonic Distortion: Ratio, expressed in dB, between the RMS sum of all aliased harmonics and the RMS value of the signal.

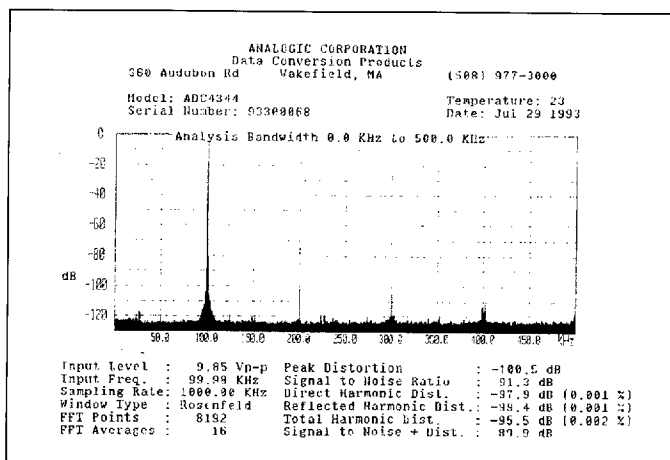


Figure 10. "Frequency Domain" Data Sheet.

Figure 11 shows a typical application circuit for the A/D converter: a four channel, high speed, high resolution A/D conversion system tied into an 8-bit bus structure. This circuit could be part of the front end of a medical imaging system, an ATE system or a sampling oscilloscope. The 16-bit resolution provides 96 dB dynamic range for each channel, and the 500 kHz throughput rate provides approximately 125 kHz throughput per channel. (In certain CT imaging applications, it may be possible to multiplex as many as 24 channels into the A/D converter.)

For multiplexed inputs, the high input impedance of the on board buffer input is required. By addressing the multiplexer at the time of the ADC trigger (Figure 5), the mux and buffer settling times do not add to the system throughput rates.

For interfacing into a 16-bit bus, the Tri-state latch or digital buffers may still be required to prevent coupling of high frequency noise from the microprocessor bus into the A/D converter. Note that in Figure 11, the signal return is NOT tied to the external common ground-plane return but instead is common at a strategic point inside the A/D converter.

Both the ability of the A/D converter Sample-and-Hold amplifier to acquire new data to within ± 1 LSB after a full-scale step change at the analog input, and the superb dc characteristics exhibited by the A/D converter, are key factors in establishing this part as the ideal choice for high speed, high performance data acquisition systems.

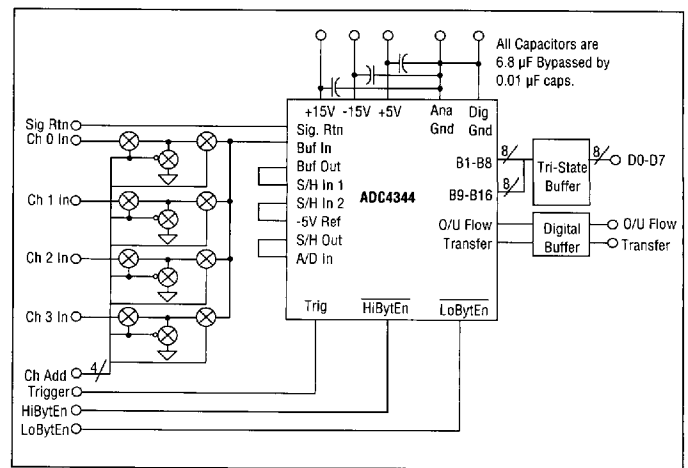


Figure 11. ADC4344 Configured for: 4-CH input, 0V to +10V input range, true binary data driving an 8-bit bus.

A1	+15V	B1	+5V	B2	+5V
A2	AGND	B3	DGND	B4	DGND
A3	-15V	B5	N.C.	B6	N.C.
A4	BUFFER IN	B7	N.C.	B8	N.C.
A5	BUFFER OUT	B9	N.C.	B10	N.C.
A6	A/D IN	B11	BIT1	B12	BIT1
A7	S&H OUT	B13	BIT2	B14	BIT3
A8	S&H IN1	B15	BIT4	B16	BIT5
A9	S&H IN2	B17	BIT6	B18	BIT7
A10	SIG RTN	B19	BIT8	B20	BIT9
A11	SIG RTN	B21	BIT10	B22	BIT11
A12	SIG RTN	B23	BIT12	B24	BIT13
A13	+5V REF	B25	BIT14	B26	BIT15
A14	OFF-SET ADJ	B27	BIT16	B28	TRIGGER
A15	GAIN ADJ	B29	TRANSFER	B30	LOBYTE ENB
A16	-5V REF	B31	HIBYTE ENB	B32	O/U FLOW

Figure 13. ADC4345 Pin Assignment.

Ordering Guide

Simply Specify
ADC4344M – 1 MHz
ADC4345M – 500 kHz

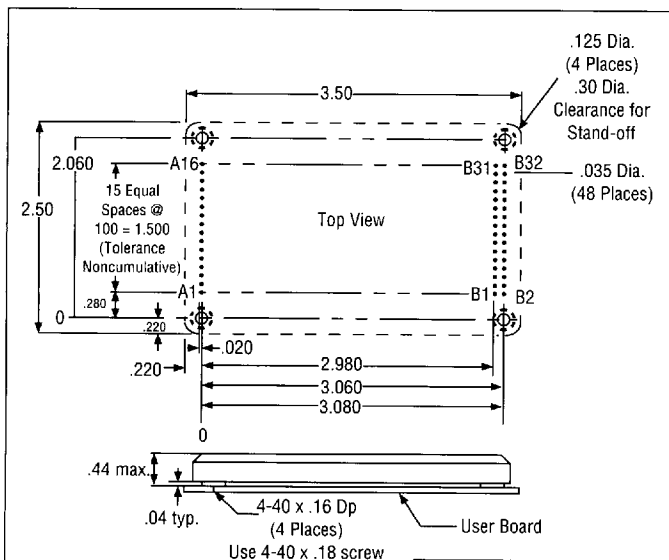
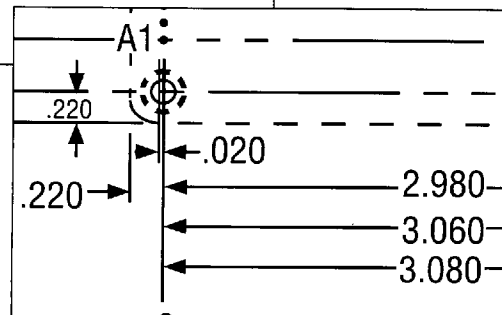


Figure 12. ADC4344/ADC4345 Mechanical.



Analogic Corporation
Data Conversion Products Group
360 Audubon Road
Wakefield, MA 01880-9863, USA
Tel: (508) 977-3000
Fax: (617) 245-1274
Technical support: (800) 446-8936

European Sales Centre
Analogic Ltd.
Ascot House
Doncastle Road
Bracknell, Berks. RG12 8PE
England
Tel: 44-344-860111
Fax: 44-344-860478

ANALOGIC
The World Resource
for Precision Signal Technology